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1	m	ĀA	5,485,630	Jan. 16, 1996	Lee, et al.				BF	CEIVED
$ \mathcal{L} $	/-	AB	5,828,403	Oct. 27, 1998	DeRodeff, et al.				•	v n 8 2002

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5,946,301

5,982,741

6,208,833

Aug. 31, 1999

Nov. 9, 1999

March 27, 2001

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

Swanson, et al.

Preschutti, et al.

Ethier

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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					U.S. PATENT DOCU	MENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS		SUBCLAS		FILING DATE ( APPROPRIATE)		(IF		
1	AA	5,544,161	08/06/96		Bigham et al.	370/58		.1	370/60					
In	AB	6,021,158	02/01/00		Schurr et al.	Schurr et al. 3		1	375/220					
In	AC	6,041,056	03/21/00		Bigham et al.		370/395 370/		370/401			<del></del>		
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